

Magnetic and structural properties of FePt L1₀ thin films

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FePt thin films in the L1₀ phase are interesting candidates for high-density magnetic recording media due to their large perpendicular magnetocrystalline anisotropy¹. In the present work two series of epitaxial Fe_{1-x}Pt_x (30 nm) films were grown through MBE on MgO(100) substrates. In the first series, the film composition was kept constant while the substrate temperature was varied between 400°C and 650°C. In the second series the substrate temperature was kept constant at 500°C while the stoichiometry was varied in the range of 43 – 71 at.% Pt. The purpose was to study the perpendicular magnetocrystalline anisotropy and its relation to the structural properties of the thin films.

The FePt thin films were characterized with vibrating sample magnetometry, x-ray diffraction, Rutherford backscattering and CEMS. From the out-of-plane magnetization loops the coercivity is extracted for the different samples. The coercivity first increases with increasing substrate temperature, peaking at 500 – 550°C, and then rapidly drops, as illustrated in figure 1.(a). A similar dependence is observed for the normalized out-of-plane-lattice parameter. These results are in agreement with what has been reported by Farrow et al². Figure 1.(b) shows the concentration dependence of the coercivity for the second series. The optimal coercivity corresponds to a 5 to 10% excess of Pt. These results show that the magnetic hardness of the FePt L1₀ films can be manipulated through the preparation conditions, i.e. the substrate temperature during deposition and the composition of the FePt film. We have also found a correlation between the magnetic hardness and the structural ordering.

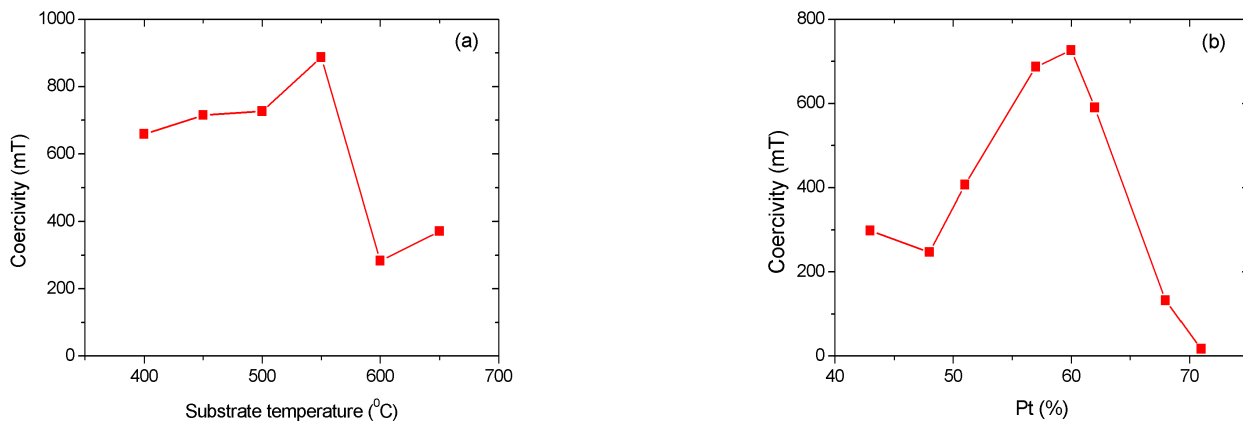


FIG. 1: The substrate temperature and concentration dependence of the coercivity of Fe_{1-x}Pt_x (30 nm) L1₀ thin films.

¹ A. Moser, K. Takano, D.T. Margulies, M. Albrecht, Y. Sonobe, Y. Ikeda, S. Sun, and E. E. Fullerton, *J. Phys. D: Appl. Phys.* **35** (2002), R157–R167.

² R.F.C. Farrow, D. Weller, R.F. Marks, M.F. Toney, S. Hom, G.R. Harp, and A. Cebollada, *Appl. Phys. Lett.* **69** (1996), 1166.